| High Voltage MOSFET |  | IXTP 01N100D |  |
| :---: | :---: | :---: | :---: |
| N-Channel, Depletion Mode |  |  |  |
|  |  |  |  |
| Symbol | Test Conditions | Maximum Ratings |  |
| $\mathrm{V}_{\text {Dss }}$ | $\mathrm{T}_{J}=25^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$ | 1000 | V |
| $V_{\text {DGR }}$ | $\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C} ; \mathrm{R}_{\mathrm{GS}}=1 \mathrm{M} \Omega$ | 1000 | V |
| $\mathrm{V}_{\text {GS }}$ | Continuous | $\pm 20$ | V |
| $\mathrm{V}_{\text {Gsm }}$ | Transient | $\pm 30$ | v |
| $\mathrm{I}_{\mathrm{D25}}$ | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C} ; \mathrm{T}_{j}=25^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$ | 100 | mA |
| $\mathrm{I}_{\text {om }}$ | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$, pulse width limited by $\mathrm{T}_{J}$ | 400 | mA |
| $\mathrm{P}_{\mathrm{D}}$ | $\mathrm{T}_{\mathrm{c}}=25^{\circ} \mathrm{C}$ | 25 | w |
|  | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ | 1.1 | w |
| T |  | $-55 \ldots+150$ | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{Jm}}$ |  | 150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {stg }}$ |  | $-55 \ldots+150$ | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{L}}$ | 1.6 mm (0.063 in.) from case for 10 s | 300 | ${ }^{\circ} \mathrm{C}$ |
| Weight |  | 1 | g |


| Symbol | Test Conditions | Characteristic Values$\text { ( } \mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C} \text {, unless otherwise specified) }$ |  |  |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {Dss }}$ | $\mathrm{V}_{\mathrm{GS}}=-10 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=25 \mu \mathrm{~A}$ | 1000 |  | V |
| $\mathrm{V}_{\text {GS(If) }}$ | $\mathrm{V}_{\mathrm{DS}}=25 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=25 \mu \mathrm{~A}$ | -2.5 |  | -5 V |
| $\mathrm{I}_{\text {Gss }}$ | $\mathrm{V}_{\text {GS }}= \pm 20 \mathrm{~V}_{\mathrm{DC}}, \mathrm{V}_{\text {DS }}=0$ |  |  | $\pm 100 \mathrm{nA}$ |
| $\mathrm{I}_{\text {oss(off }}$ | $\mathrm{V}_{\mathrm{DS}}=\mathrm{V}_{\text {DSS }}, \mathrm{V}_{\text {GS }}=-10 \mathrm{~V}$ | $\begin{aligned} & \mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C} \\ & \mathrm{~T}_{\mathrm{J}}=125^{\circ} \mathrm{C} \end{aligned}$ |  | $\begin{aligned} 10 & \mu \mathrm{~A} \\ 250 & \mu \mathrm{~A} \end{aligned}$ |
| $\mathrm{R}_{\text {DS(on) }}$ | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=50 \mathrm{~mA} \mathrm{No}$ |  | 90 | $110 \Omega$ |
| $\mathrm{I}_{\mathrm{D}(0)}$ | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=50 \mathrm{~V}$ |  | 250 | mA |



TO-220AB (IXTP)


Features

- Normally ON mode
- Low $\mathrm{R}_{\text {DS (on) }} \mathrm{HDMOS}^{\text {TM }}$ process
- Rugged polysilicon gate cell structure
- Fast switching speed


## Applications

- Level shifting
- Triggers
- Solid state relays
- Currentregulators



## Source-Drain Diode

Characteristic Values
( $\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$, unless otherwise specified)
Symbol TestConditions


TO-220 AD Dimensions

| Pins: | $\square$ $\square$ <br> k(M)C <br> 1-G <br> 3 - S |  | C <br> J1 <br> 2 - Dr <br> 4 - Dr <br> Bottom |  |
| :---: | :---: | :---: | :---: | :---: |
| SYM |  |  | MILL | TERS |
| SYM | MIN | MAX | MIN | MAX |
| A | . 170 | . 190 | 4.32 | 4.83 |
| b | . 025 | . 040 | 0.64 | 1.02 |
| b1 | . 045 | . 065 | 1.15 | 1.65 |
| c | . 014 | . 022 | 0.35 | 0.56 |
| D | . 580 | . 630 | 14.73 | 16.00 |
| E | . 390 | . 420 | 9.91 | 10.66 |
| e | . 100 |  | 2.5 |  |
| F | . 045 | . 055 | 1.14 | 1.40 |
| H1 | . 230 | . 270 | 5.85 | 6.85 |
| J1 | . 090 | . 110 | 2.29 | 2.79 |
| k | 0 | . 015 | 0 | 0.38 |
| L | . 500 | . 550 | 12.70 | 13.97 |
| L1 | . 110 | . 230 | 2.79 | 5.84 |
| ФP | . 139 | . 161 | 3.53 | 4.08 |
| Q | . 100 | . 125 | 2.54 | 3.18 |

Note 1: Pulse test, $\mathrm{t} \leq 300 \mu \mathrm{~s}$, duty cycle $\mathrm{d} \leq 2 \%$

